

Notice of References Cited	Application/Control No. 09/964,515	Applicant(s)/Patent Under Reexamination KIMURA ET AL.	
	Examiner A. M. Thompson	Art Unit 2825	Pag 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	G. Jerke et al., Hierarchical Current Density Verification for Electromigration Analysis in Arbitrarily Shaped Metallization Pattern of Analog Circuits, Proceedings of Design, Automation and Test in Europe Conference, pages 464-469, March 2002.
	V	
	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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